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Manual

**TUNER 0.3-2000 MHz  
ZPV-E3**

301.7018.02

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Fig. 2-1 Operating controls

Fig. 4-1 Block diagram of RF section

Fig. 5-1 Location of modules and adjusting elements

Parts Lists

Drawings and Diagrams

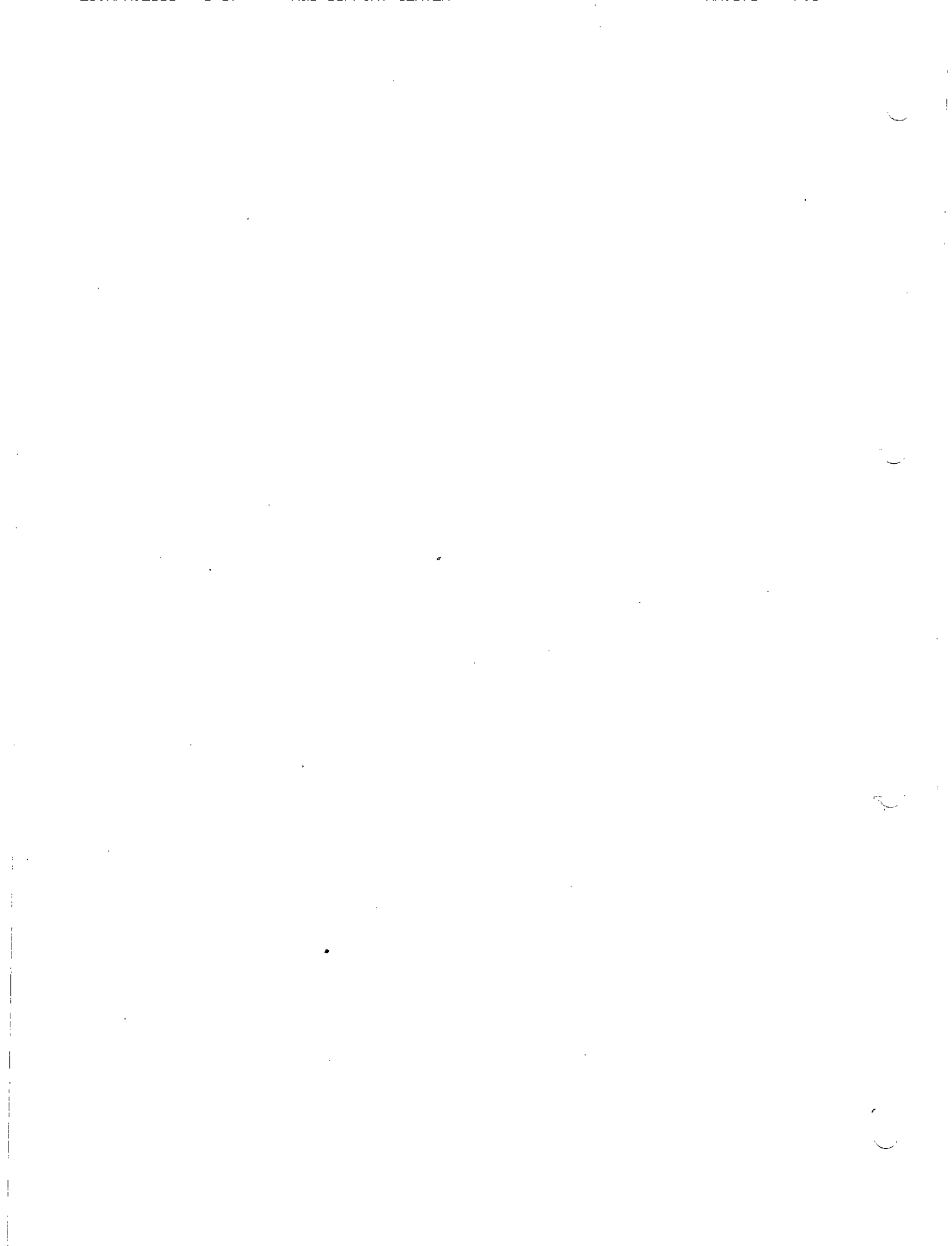
Supplement  
to Manual 301.7418 ZV  
TUNER ZPV-E3 0.3 to 2000 MHz

Important Note for Use of Tuner ZPV-E3

Meeting the performance data of the Tuner ZPV-E3 depends on the accurate setting of the operating voltages. Measure operating voltages at socket 18 on the motherboard in the basic unit ZPV. The voltages  $\pm 20$  V and 120 V should be accurate to within 0.05 V. In case of larger deviations correct by means of the potentiometers R14 and R15 in the power supply 291.6015. If the nominal value of the 120-V supply is still not obtained vary the voltage divider R6-R7. This is accomplished by connecting a variable resistor (5-k $\Omega$  potentiometer) in series with R6 and R7. By increasing the resistance of R6 the voltage is increased. By increasing the resistance of R7 the voltage is decreased.

In order not to affect the performance of the Tuner ZPV-E2 if used with the same basic unit measure prior to changing the operating voltage setting the voltage at the base of transistor T3 on the pulse generator board 237.1290 in the Tuner ZPV-E2 and after changing the operating voltage reset the measured value by means of the "pulse amplitude" potentiometer R12.

Einheiten in die Beschreibung 301.7418 ZV vor der engl. Datenblatt



2. Preparation for Use and Operating Instructions.

2.1 Legend for Fig. 2-1

No.	Engraving	Function
<u>1</u>	UNSYNC.	Indication of synchronization; when the lamp lights up, the Tuner is not synchronized.
<u>2</u>		Indication of the selected frequency range; effective only if the autoranging facility on the basic unit is disconnected.
<u>3</u>	↑	Pushbutton for increasing the frequency range step by step (indication on <u>2</u> ) if the autoranging facility is disabled.
<u>4</u>	↓	Pushbutton for decreasing the frequency range step by step (indication on <u>2</u> ) if the autoranging facility is disabled.
<u>5</u>	B	RF input socket for channel B.
<u>6</u>	LOCK.	Knob for locking and unlocking the Tuner inserted in the basic ZPV unit.
<u>7</u>	A	RF input socket for channel A.
<u>8</u>	SWEEP ON/OFF	Pushbutton for enabling and disabling the sweep mode in which the basic unit functions in purely analog operation without microprocessor; operative only in modes B and B/A with the autoranging facility of the basic unit disabled.
<u>9</u>	—	Guiding pin for plug-in Tuner.
<u>10</u>	—	Connector strip ST42 establishing the connection upon insertion of the plug-in into the basic unit.

## 2.2 Preparation for Use

### 2.2.1 Plugging into the Basic Unit

Prior to inserting the Tuner, disconnect the ZPV from the power supply. After turning the locking knob 6 to the lefthand stop, the Tuner can be plugged into the basic unit. Next turn knob 6 to the righthand stop and switch the ZPV on. The Tuner is immediately ready for operation. After disabling the autoranging facility on the basic unit, the Tuner can be operated manually and thus checked.

## 2.3 Operating Instructions

### 2.3.1 Operation with Autoranging Facility

When using the autoranging facility, the basic unit automatically selects the correct frequency subrange so that no controls have to be set on the Tuner. Sweeping is not possible in this mode.

### 2.3.2 Manual Operation without Autoranging Facility

If the autoranging facility of the basic unit is disabled, the Tuner can be manually operated. The frequency range indication 2 is operative. Buttons 3 and 4 permit the correct range to be selected in accordance with the RF signal applied to 7. If the correct frequency subrange is set and the RF level is  $> 150 \mu\text{V}$  at 7, the Tuner is synchronized and delivers, via 10, the IF signal to the basic unit. At the same time, lamp 1 goes out. The RF input 5 associated with channel B is ready for receiving an RF signal and, with such a signal applied, delivers an IF signal to the basic unit.

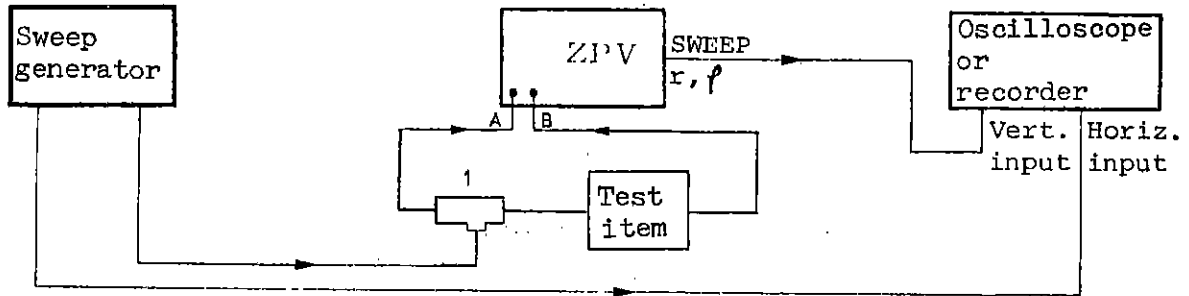
### 2.3.3 Sweeping

The sweep mode can be switched on and off with 8 if the basic unit operates in mode A or B/A and the autoranging facility is disabled. During sweep operation, purely analog signal processing takes place in the basic unit. The microprocessor monitors only the dynamic range in ratio measurements B/A.

## 2.4 Measurement Examples

### 2.4.1 Filter Measurements

#### Test setup



#### 1 Feed Unit ZPV - Z2

The characteristics of narrowband crystals and filters can be determined with the aid of a sweep generator assembly. For this purpose, the sweep mode is set using 8. Frequency and amplitude autoranging are inhibited on the basic unit, therefore it is necessary to first set the correct ranges. The sweep rate should be max. 30 MHz/s and the sweep width should not exceed 1 MHz so that the synchronization is maintained.

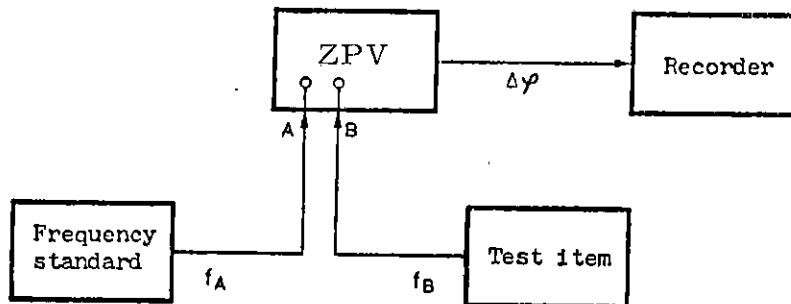
This test assembly permits the passband characteristic, the phase response and the group delay to be displayed on an oscilloscope or plotted with a recorder.



## 2.4.2 Frequency Comparison

Many methods employed for the frequency adjustment of precise oscillators or for the measurement of frequency stability yield a result of adequate accuracy only after a relatively long measurement time. Using the Vector Analyzer this time can be cut down considerably. For example, the ZPV permits two frequencies of 1 MHz to be compared within one minute with an accuracy of  $3 \times 10^{-10}$ .

### Test setup



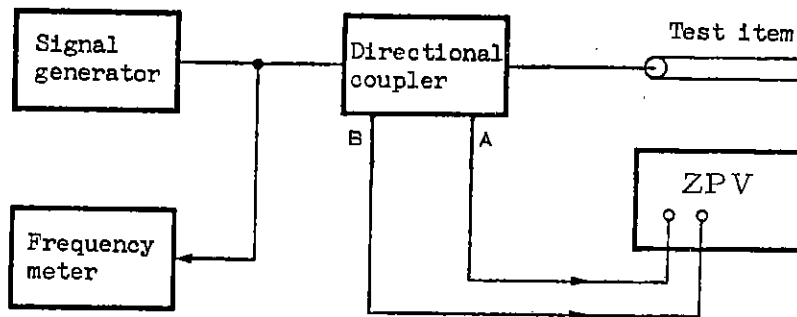
### Comparison of two very accurate frequencies

Provided that the two input frequencies  $f_A$  and  $f_B$  are almost equal, their phase difference varies very slowly. The difference frequency  $\Delta f$  is obtained from the recorded phase difference  $\Delta\varphi$  and the measurement time  $\Delta t$ :

$$\Delta f = \frac{\Delta\varphi}{360^\circ \times \Delta t}$$

### 2.4.3 Measuring the Electrical Length of Cables

#### Test setup



#### Measuring the electrical length of a cable

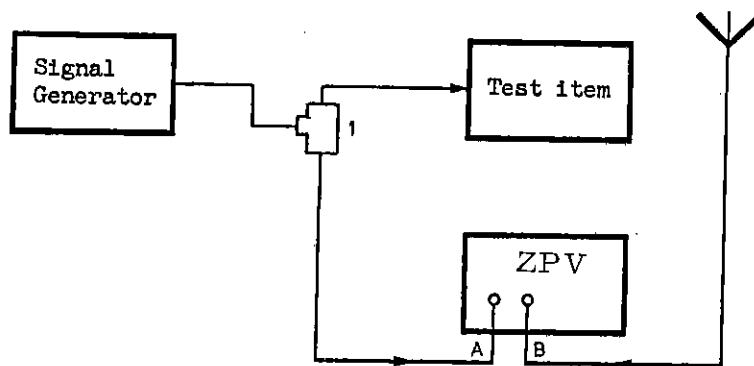
Thanks to its high phase resolution the ZPV can be used for the accurate measurement of the electrical length of cables. The forward and the reflected voltage are derived via a directional coupler and the ZPV measures the phase difference. If the electrical length of the cable is an integral multiple of  $\lambda/2$ , then the ZPV indicates the phase difference  $0^\circ$ . The test setup is therefore suitable to determine the electrical length of cables differing from multiples of  $\lambda/2$ . The measuring error decreases proportionally with increasing test frequency.

First set the phase meter to  $0^\circ$  while no cable is connected, i.e. the directional coupler output is open. Then connect the cable and read the phase difference on the ZPV. If, for example, a test frequency of 41.666 MHz is selected, a phase difference of  $1^\circ$  corresponds to 10 mm electrical length of the cable. The number of  $\lambda/2$  waves must of course be counted to determine the overall cable length.

To adjust two cables for equal electrical length, the phase difference at the output of the cables can be measured, the two cable inputs being connected in parallel to the signal generator. The indicated phase difference is proportional to the difference in electrical length of the cables.

#### 2.4.4 Antenna Measurements

##### Test setup



1 Feed Unit ZPV-Z2

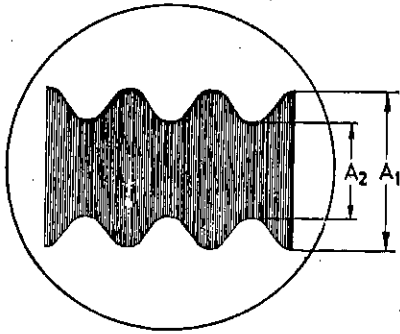
##### Measuring the radiation pattern of an antenna

Thanks to its uniformly high selectivity in the whole frequency range of 1 to 1000 MHz the Vector Analyzer can be used as a test receiver for the measurement of antenna radiation patterns. The ZPV is synchronized to the test frequency via channel A, while channel B is connected to the antenna. The bandwidth of channel B is 30 Hz in the range  $< 100 \mu\text{V}$  and 2 kHz in the other ranges. Other electrical or magnetic fields can be measured in the same way as radiation patterns.

Because of multiple reception due to mixing with harmonics ( $f_n = nf_{\text{vco}} \pm 20 \text{ kHz}$ ), the test system has to be protected from unwanted fields or the useful level has to be selected sufficiently higher than the occurring unwanted levels.

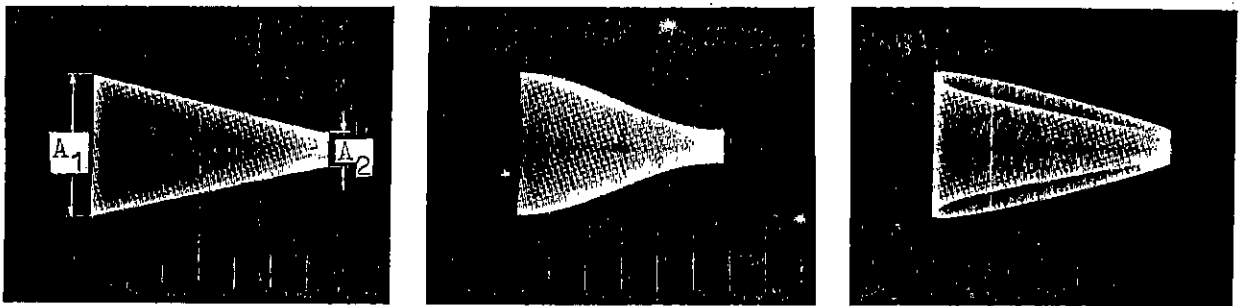
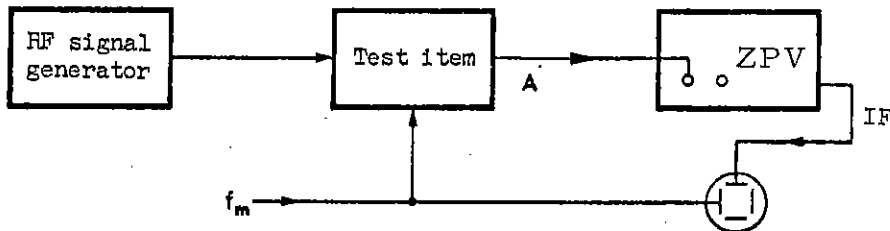
#### 2.4.5 Modulation-depth Measurement

The Vector Analyzer ZPV converts the received RF signal faithfully to IF. Connecting an AF oscilloscope to the IF output one obtains a scanning oscilloscope for RF signals in the range 1 to 1000 MHz. Modulation depth  $m$  is calculated from the lengths  $A_1$  and  $A_2$  measured on the screen:



$$m = \frac{A_1 - A_2}{A_1 + A_2} \times 100\%$$

If the modulation signal is available, the nonlinearity and phase shift of the modulator can also be measured. The modulation frequency must in this case be low enough to make sure that the scanning bandwidth and the bandwidth of the IF circuits do not cause an attenuation or phase shift of the modulated signal. The following test setup is used:



Measurement of modulation trapezium

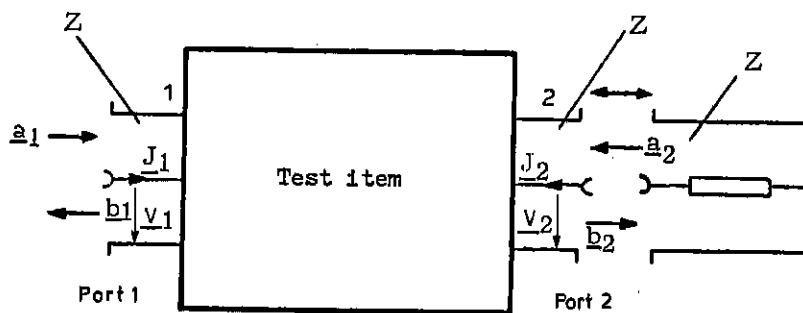
The lefthand oscillogram shows the modulation trapezium of a perfectly modulated signal; the modulation depth can be determined from  $A_1$  and  $A_2$ , it is 60%. The other two oscillograms show nonlinearity (centre) and phase shift (right).

#### 2.4.6 Measurement on Four-terminal Networks

The following measurements on four-terminal networks are possible only when using the s-parameter Measurement Option ZPV - B2.

##### 2.4.6.1 General

Accurate measurement of the h, y and z parameters is difficult in the UHF range since a current measurement is hard to perform in this range. The s-parameters can be determined without voltage and current measurements, the wave quantities being obtained by a measurement using directional couplers. Assuming a forward wave at each of the two ports of a four-terminal network, the wave is reflected, absorbed or partly transmitted by the network.



Test item with complex wave quantities  $\underline{a}_1$ ,  $\underline{a}_2$ ,  $\underline{b}_1$ ,  $\underline{b}_2$ ; match-termination with characteristic impedance  $Z$  shown on right

The effect at the ports is described by the reflected waves  $\underline{b}$  as functions of the forward waves  $\underline{a}$ .

$$\underline{b}_1 = \underline{s}_{11}\underline{a}_1 + \underline{s}_{12}\underline{a}_2 \quad (1)$$

$$\underline{b}_2 = \underline{s}_{21}\underline{a}_1 + \underline{s}_{22}\underline{a}_2 \quad (2)$$

The coefficients  $s_{11}$ ,  $s_{12}$ ,  $s_{21}$  and  $s_{22}$  are called the s parameters. The two equations, whose terms are generally complex, fully describe the four-terminal network. If the test item is terminated without reflection at port 2,  $b_2 = 0$  as shown in the above diagram, the  $a_2 = 0$  and equation (1) yields  $s_{11} = \frac{b_1}{a_1}$ . Thus  $s_{11}$  is the input reflection factor at port 1 if port 2 is match-terminated. The equations for the other s-parameters are obtained in the same way:

Meaning of s-parameters

$$s_{11} = \frac{b_1}{a_1} \quad \left| \quad a_2 = 0 \right.$$

$$s_{22} = \frac{b_2}{a_2} \quad \left| \quad a_1 = 0 \right.$$

$$s_{12} = \frac{b_1}{a_2} \quad \left| \quad a_1 = 0 \right.$$

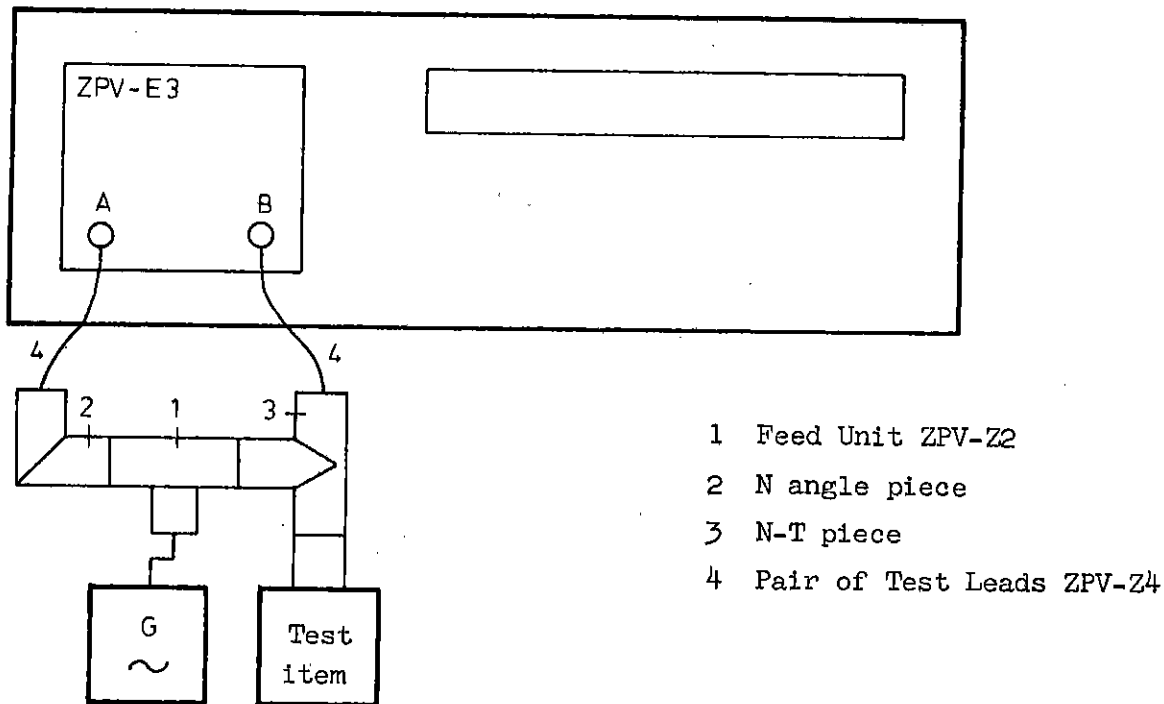
$$s_{21} = \frac{b_2}{a_1} \quad \left| \quad a_2 = 0 \right.$$

The two quantities are input reflection factors which convey information on input impedance and matching. During measurement the corresponding output must be match-terminated, as indicated by the conditions  $a_1 = 0$  and  $a_2 = 0$ .

$s_{21}$  is the forward transmission factor,  $s_{12}$  the backward transmission factor. During measurement the corresponding output must be match-terminated.

## 2.4.6.2 Parameter Measurement without Directional Coupler and VSWR Bridge

### 2.4.6.2.1 Reflection Measurement according to the T Method

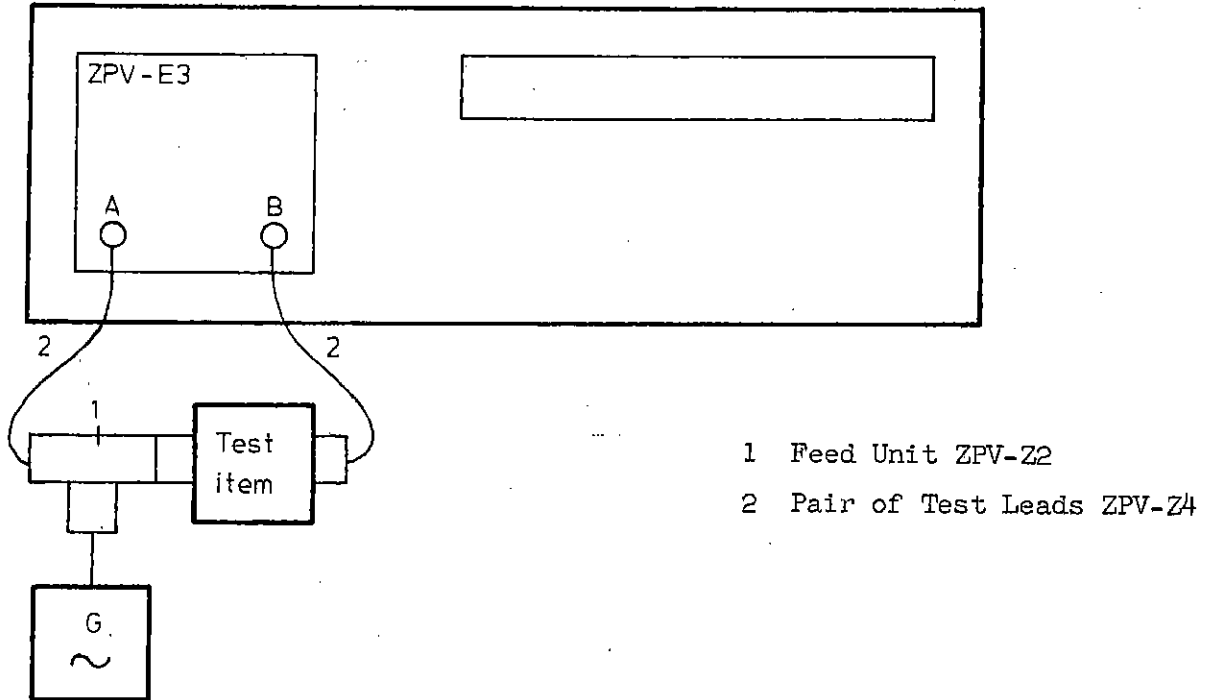


Test setup for measuring the reflection factor  
without directional coupler and VSWR bridge

In conjunction with the Tuner ZPV-E3, the Vector Analyzer ZPV permits the measurement of reflections, impedances and admittances using a simple test setup with an N-T section as shown above. During such measurements, the DIR. COUPL. button on the basic unit must not be pressed. The measuring plane is in the centre of the N-T section and can only be shifted by means of desk-calculator control.

When adjusting the test setup (S11, S22 cut in), the test item must be replaced by a reflection-free termination (e.g. RNA), the PARAM. CAL. button on the basic unit being pressed.

### 2.4.6.2.2 Transmission Factor Measurement

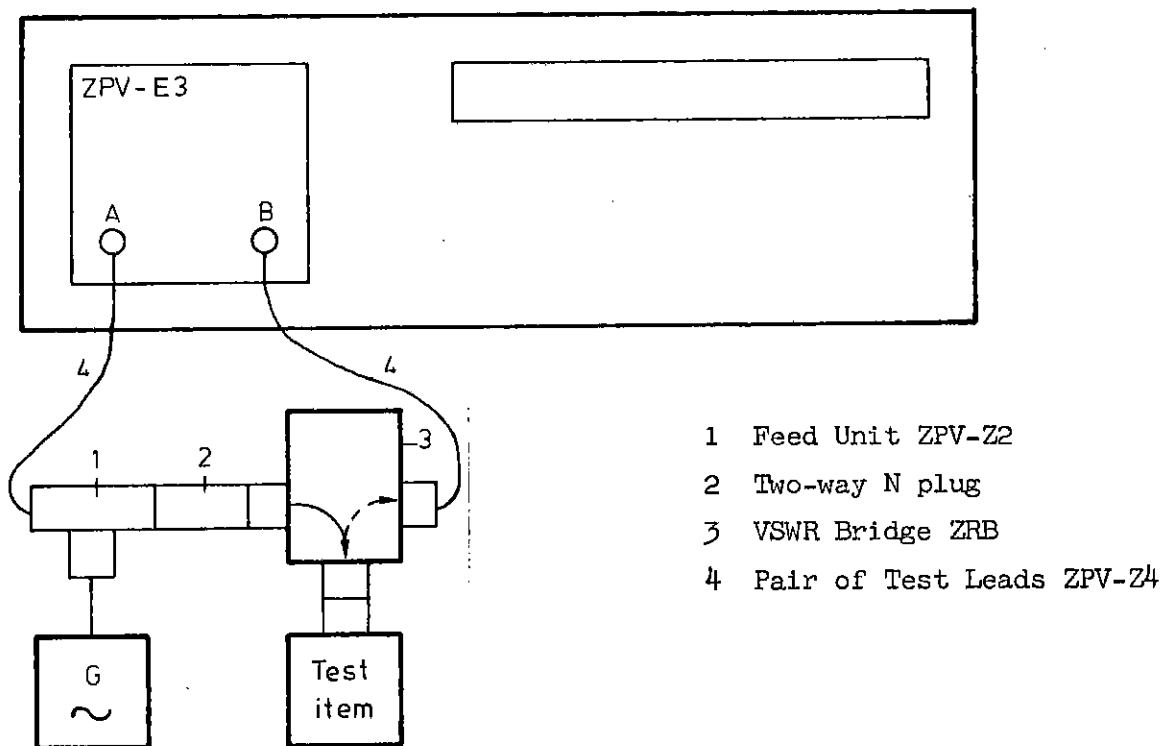


Test setup for measuring the transmission factor

Owing to the coaxial test inputs of the Tuner ZPV-E3, this test setup is of particularly simple design at reduced costs. When adjusting the test setup (button S11/S22 on basic unit pressed), the units are interconnected without the test item and button PARAM. CAL. is pressed.



### 2.4.6.3 Reflection Factor Measurement with a VSWR Bridge



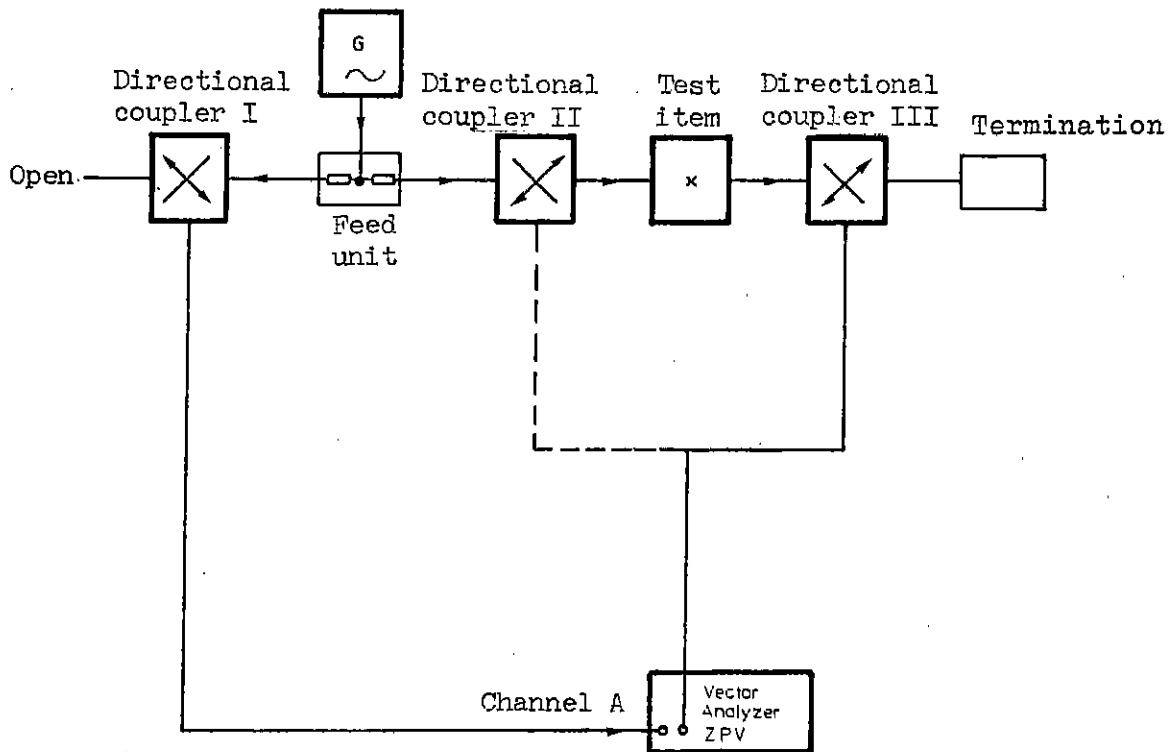
Test setup for measuring the reflection factor with a VSWR bridge

VSWR bridges permit reflections, impedances and admittances to be measured and then directly indicated on the basic unit, the button DIR. COUPL. being pressed. The measuring plane is at the test-item input of the VSWR bridge and can be shifted by inserting an electrical length into the lead to the A channel.

When adjusting the test setup (button S11/S22 depressed), the test item is replaced by a termination (e.g. RNA) and the button PARAM. CAL. on the basic unit is pressed.

## 2.4.6.4 Parameter Measurements

### 2.4.6.4.1 Parameter Measurement with High Voltage at Test Item using Directional Couplers



Test setup for measuring s-parameters with high voltage at test item

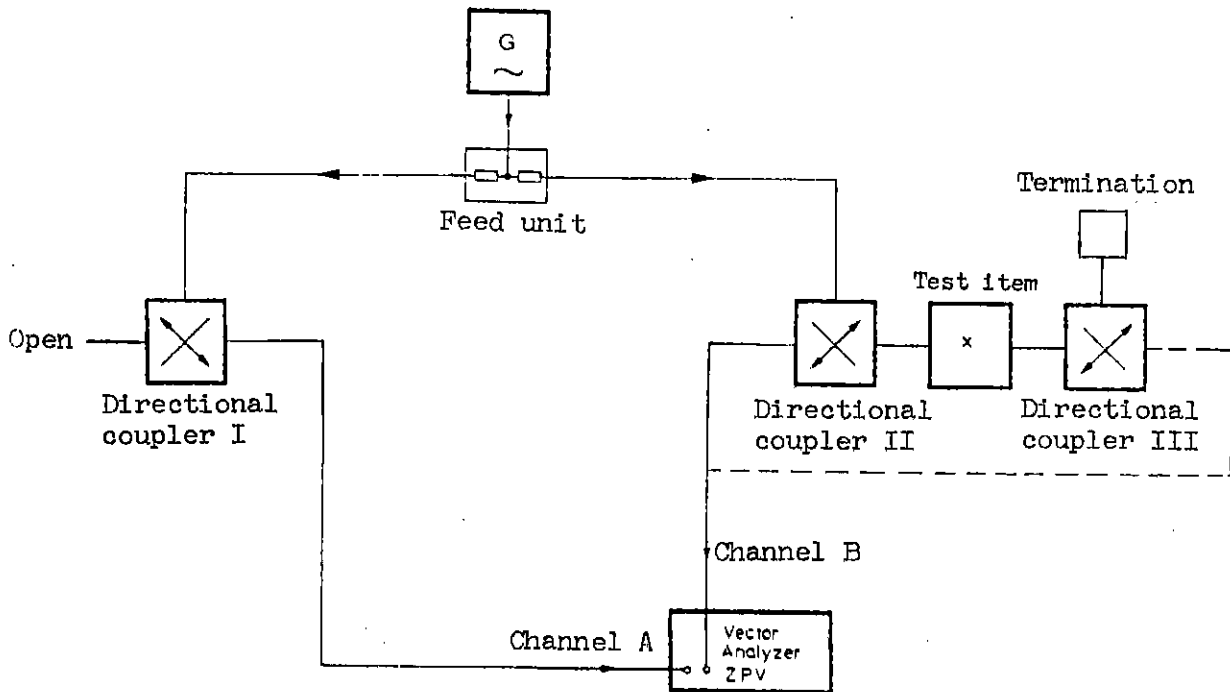
Since the s-parameters, by definition, represent quotients of two waves, the ZPV is used in the ratio meter mode. The measurement range of the transmission factors  $s_{12}$  and  $s_{21}$  and of the reflection factors  $s_{11}$  and  $s_{22}$  depends on the quality of the directional couplers. Reflection factors  $> 1$  are obtained with test items having a negative incremental resistance, e.g. amplifiers or oscillators using tunnel diodes.

The test setup is shown schematically above. Directional coupler I compensates for the frequency responses of directional couplers II and III. The unused test output of directional couplers II and III is to be provided with a reflection-free termination. The ZPV indicates either the measured s-parameters with respect to magnitude and phase or directly the real and imaginary components.

When adjusting the test setup for measuring  $s_{11}$  and  $s_{22}$  the test item is replaced by a short circuit and button PARAM. CAL. on the basic unit is pressed (the  $s_{11}$ ,  $s_{22}$  mode should be selected).

When adjusting the test setup for measuring  $s_{21}$  and  $s_{12}$ , the units are interconnected without the test item and button PARAM. CAL. on the basic unit is pressed, the  $s_{21}$ ,  $s_{12}$  mode being selected.

2.4.6.4.2 Parameter Measurement with Low Voltage at Test Item  
using Directional Couplers



Test setup for measuring s-parameters with low voltage at test item

In the test setup shown in section 2.4.6.4.1, about half the generator voltage, depending on the input reflection factor  $s_{11}$ , is applied to the test item. If the test item tolerates only a low voltage, for instance during measurements on semiconductors and antenna amplifiers, the test setup shown above is used. It differs from the former only in that the feed-in connections are interchanged with the test connections on the directional couplers I and II. With  $s_{11} < 0.3$ , the voltage across the test item is about the same as that measured in channel B. The unused test output of directional couplers II and III must be provided with a reflection-free termination. Switching over can be effected with an RF relay matrix (e.g. PSU). Adjustment and performance test are made in accordance with section 2.4.6.4.1.

#### 2.4.7 Group Delay Measurements

The constancy of the group delay through a transmission network is a measure of its waveform fidelity. Since the group delay is, by definition,  $d\varphi/d\omega$ , it can be measured with the aid of the relation  $(\varphi_2 - \varphi_1)/(\omega_2 - \omega_1)$  if the differences are chosen small enough. The Group Delay Measurement Option ZPV - B3 permits the group delay or the group delay variation - referred to a specified basic group delay - to be indicated directly on the basic unit.

With the ZPV - B3 only measurements on coaxial systems are possible. These measurements can be performed either in the manual mode by pressing two buttons and adjusting the generator accordingly or in the automatic mode which requires a generator whose frequency modulation can be DC-voltage-controlled. With automatic operation calibration is made with the aid of the calibrating cable supplied with the Group Delay Measurement Option and by pressing the CAL. button on the basic unit.

3. Maintenance and Repair

3.1 Required Measuring Equipment and Accessories

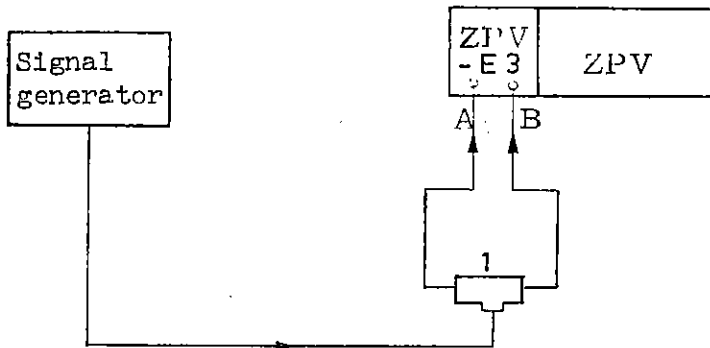
No.	<ul style="list-style-type: none"> <li>○ Instrument required</li> <li>● Recommended R&amp;S model</li> </ul>	Type	Order No.
1	<ul style="list-style-type: none"> <li>○ Signal generator 0.1 - 1000 MHz, 2 V/50 Ω</li> <li>● Signal Generator 15 Hz - 525 MHz plus 1.05-GHz Frequency Range Extension or 1.05-GHz Frequency Doubler</li> <li>● Decade Frequency Generator 10 kHz - 1000 MHz</li> <li>● Power Signal Generator 25 - 1000 MHz</li> <li>● UHF Power Signal Generator 280 - 2750 MHz</li> </ul>	<ul style="list-style-type: none"> <li>SMDU</li> <li>SMDU - B3</li> <li>SMDU - B5</li> <li>SMDS</li> <li>SMLU</li> <li>SLRD</li> </ul>	<ul style="list-style-type: none"> <li>249.3011...</li> <li>249.9484.02</li> <li>275.1312.02</li> <li>154.8723.52</li> <li>200.1009...</li> <li>100.4194.02</li> </ul>
2	<ul style="list-style-type: none"> <li>○ Frequency meter 18 - 22 kHz, sensitivity min 10 μV</li> <li>● SMDU frequency meter (see No. 1)</li> </ul>		
3	<ul style="list-style-type: none"> <li>○ RF voltmeter 0.1 - 1000 MHz, error &lt; 1%</li> <li>● RF-DC Millivoltmeter in conjunction with No. 5</li> </ul>	URV	216.3612.02
4	<ul style="list-style-type: none"> <li>○ Power meter 0.2 MHz - 2 GHz, error &lt; 1%</li> <li>● Microwave Power Meter with 50-Ω Probe in conjunction with No. 5</li> </ul>	<ul style="list-style-type: none"> <li>NRS</li> <li>NRS-Z</li> </ul>	<ul style="list-style-type: none"> <li>100.2433.92</li> <li>100.2440.05</li> </ul>
5	<ul style="list-style-type: none"> <li>○ Digital voltmeter 1 mV - 1 V, 0 - 20 kHz, error &lt; 0.5%</li> </ul>		
6	<ul style="list-style-type: none"> <li>○ Lowpass filter 60 - 1000 MHz, 30 - 60 dB, 50 Ω</li> </ul>		

No.	<ul style="list-style-type: none"> <li>○ Instrument required</li> <li>● Recommended R&amp;S model</li> </ul>	Type	Order No.
7	<ul style="list-style-type: none"> <li>○ 50-<math>\Omega</math> attenuators 0 - 2 GHz, 5/10/60 dB</li> </ul>		
8	<ul style="list-style-type: none"> <li>○ 50-<math>\Omega</math> Termination <math>r &lt; 1\%</math>, 0 - 2 GHz</li> </ul>	RNA	

### 3.2 Checking the Rated Specifications

#### 3.2.1 Performance Checking

##### Test setup



1 Feed Unit ZPV - Z2

The Tuner ZPV - E2 is inserted into the Vector Analyzer ZPV in accordance with section 2.2.1 and fixed mechanically.

Disconnect the frequency autoranging facility on the basic unit. Set the generator output voltage to 0 V. The red lamp UNSYNC 1 (Fig. 2-2) and one of the green lamps associated with the frequency range indication 2 should light up. By pressing buttons 3 and 4 it must be possible to switch over the frequency ranges accordingly in the corresponding order.

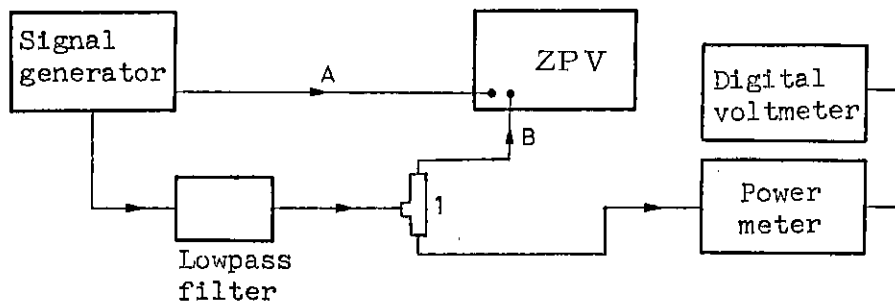
Set an output level of about 200 mV unmodulated and any frequency between 0.1 and 1000 MHz on the signal generator. Select the frequency range corresponding to this frequency by hand (button 3 or 4). Now the red lamp UNSYNC should go out and the applied voltage of about 100 mV should be indicated

in both channels on the ZPV (modes A (B), LIN). Check for correct synchronization in all frequency ranges.

Switch on the frequency autoranging facility on the basic unit. It should track the generator frequency over the entire range. Connect a 60-dB/50- $\Omega$  attenuator pad between the feed unit and the input socket 5 of channel B. Set the generator frequency to 1 to 10 MHz and the amplitude in channel A to 30 mV. A level of 30  $\mu$ V should be indicated for the B channel.

### 3.2.2 Frequency Dependence of Amplitude Conversion

#### Test setup



#### 1 Insertion Adapter ZPV - Z1

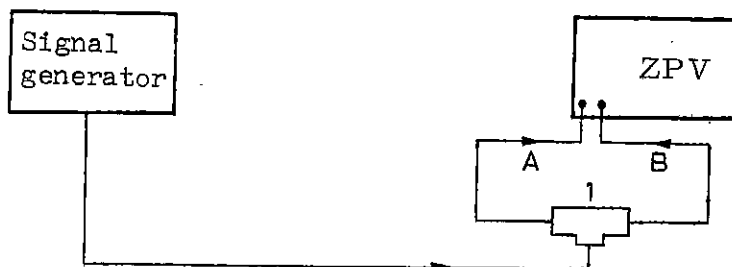
The frequency response is checked with a calibrated signal. To increase the accuracy and to keep the harmonics of the calibrated signal at least 30 dB down, either one of the signal generators recommended in section 3.1 or a lowpass filter should be used. The measurement accuracy then depends on the accuracy of the power meter alone.

- Calibrate the power meter in the 1-mW measuring range in accordance with its operating instructions. To increase the accuracy, the power meter should be used in conjunction with a digital voltmeter and the calibration curve should be taken into account.
- Set the signal generator frequency to 10 MHz. Set the unmodulated output to 1 mW (0 dBm) with the aid of the power meter.
- Select the corresponding frequency range on the basic unit. Lamp UNSYNC should go out.

- Select mode B, LIN.
- Any departure of the indicated value from nominal (= 223.5 mV) should be within the tolerance limits given in the specifications.
- Repeat the measurement at different frequencies in the specified range.
- Carry out the same measurements for channel A.

### 3.2.3 Differential Phase/Frequency Response

#### Test setup



#### 1 Feed Unit ZPV - Z2

The differential phase response of the Tuner ZPV - E2 is measured in a symmetrical test setup.

- Set an unmodulated reference frequency between 1 MHz and 10 MHz on the signal generator. The output level is adjusted for 100 mV at the ZPV. Select mode A (or B), LIN.
  - Switch in the frequency autoranging facility on the ZPV.
  - Store the reference phase at the reference frequency ( $\phi_{REF. STORE}$ ).
  - Vary the generator frequency over the entire range.
- The phase variation indicated on the ZPV should not exceed the values specified in the data sheet.



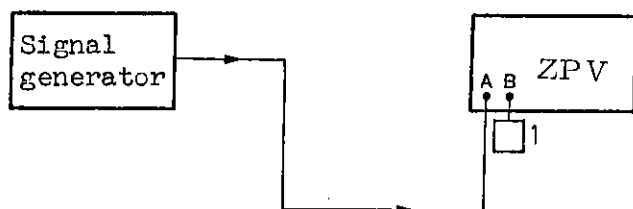
### 3.2.4 Differential Amplitude/Frequency Response

Test setup same as under 3.2.3.

- Set an unmodulated reference frequency between 1 MHz and 10 MHz on the signal generator. Adjust the output level for 100 mV at the ZPV. The ZPV should be operated in mode A (B), LIN.
- Change the ZPV mode to B/A, LIN. Store the reference level (LEVEL REF. STORE).
- When varying the generator frequency over the entire range from 0.1 MHz to 1000 MHz, the departure from the 100% indication should not exceed the values given in the specifications.

### 3.2.5 Crosstalk Attenuation of Test Channels

Test setup



1 50- $\Omega$  termination

The test signal is applied only to channel A; channel B is terminated with 50  $\Omega$ . Prior to the measurement, the ratio B/A is calibrated at about 100 mV (mode B/A, dB (REL.)) using the test setup under 3.2.3 and the value is stored (LEVEL REF. STORE).

- Set a frequency of 300 MHz on the signal generator; the output level is 1 V unmodulated.
- The amplitude of the crosstalk signal is indicated in dB on the ZPV.
- Repeat the measurement at 500 MHz, 800 MHz and 1000 MHz. The nominal crosstalk attenuation is given in the specifications.

### 3.2.6 Inherent Noise

Test setup same as under 3.2.5.

- Select a frequency of 2 MHz on the signal generator. Adjust the generator output level such that about 3 to 10 mV are indicated for reference channel A.
- Select mode B, LIN on the ZPV and disconnect the filter (button FILTER). The indicated noise voltage should be  $< 10 \mu\text{V}$  (typ.).

### 3.3 Mechanical Maintenance

The Tuner is a compact, exchangeable plug-in of the ZPV. To establish perfect contact to the basic unit, the plug-in is fitted with a connector strip and a guiding pin on the rear panel, both elements being freely adjustable to compensate for the tolerances.

#### 4. Circuit Description

The Tuner ZPV - E3 of the Vector Analyzer ZPV converts the signal received via the inputs A and B (7 and 5 in Fig. 2-1) to the IF over a wide frequency range of 300 kHz to 2000 MHz. In conjunction with the basic unit, the Tuner is synchronized fully automatically over the entire frequency range to the signal in reference channel A. For some special cases manual frequency-range selection is possible with the aid of pushbuttons. Then the instrument is automatically synchronized in the selected subrange.

The signals received via the input sockets are converted in the ZPV - E3 with the correct phase and amplitude into a fixed IF of 20 kHz. The input impedance is 50  $\Omega$ . The measured values are evaluated in the basic unit at the fixed IF.

##### 4.1 Frequency Conversion of the Test Signal

See Fig. 4-1 and circuit diagram 301.7018.

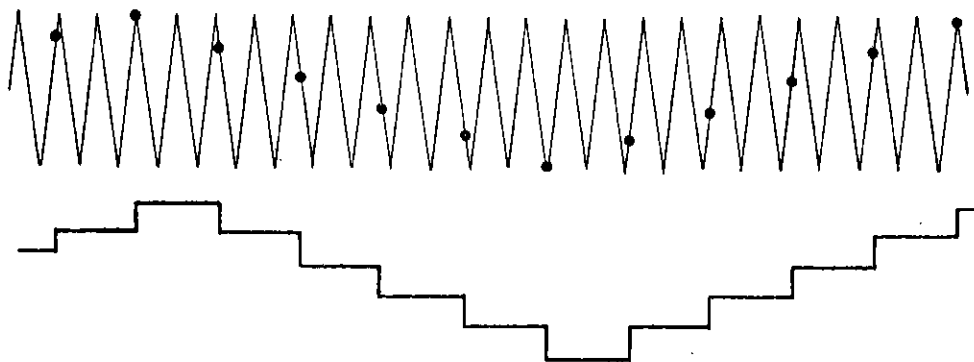


Fig. 4-2 Frequency conversion by sampling

The method of sampling the RF signal used in the Tuner ZPV - E2 permits expansion of the signal with respect to time so that it can be processed at a much lower IF. The expansion is performed by sampling with the correct phase after omitting  $n$  periods of the RF signal and storing the information between two sampling points (Fig. 4-2).

The accuracy of the expanded display is determined by the number of sampling points during one period of the represented waveform, i.e. by the ratio of the sampling frequency to the IF.

The sampled voltage is stored in the capacitor  $C_s$  (Fig. 4-3) which is temporarily connected to the voltage source via switch  $S$ . The capacitor charges to the mean value of the voltage applied. During the hold time between two sampling points the storage capacitor is discharged only by the input resistance  $R_{in}$  of the subsequent buffer amplifier. The resulting voltage variation is negligible due to the long time constant  $C_s \times R_{in}$ .

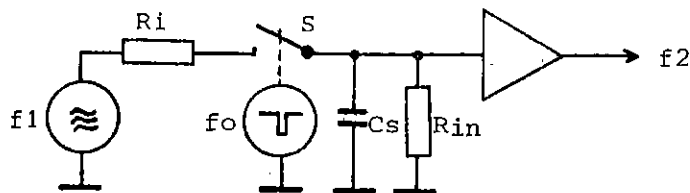


Fig. 4-3 Sampling principle

The frequency  $f_2$  of the converted signal is the difference between  $n$  times the scanning frequency  $f_o$  and the input frequency  $f_1$ :

$$f_2 = n f_o \pm f_1 \quad (1)$$

To keep the intermediate frequency  $f_2$  constant and independent of the input frequency, the scanning frequency is controlled accordingly. The frequency control circuit compares the nominal with the actual frequency and produces a voltage proportional to the IF deviation. This voltage is processed in the control amplifier Y15 and applied to the variable oscillator Y16 (Fig. 4-1). Its frequency is controlled such that the remaining deviation is reduced to a minimum. The pulse generator driven by the VCO produces narrow pulses which, after symmetrization, are taken to the circuits for sampling the input signal. The pulses are produced together for both channels, the phase noise being thus suppressed to a large extent. The required decoupling is achieved by the configuration of the two channels and by the use of diode switches. The adjustable delay network Y19 located between the pulse generator Y12 and the following amplifier B, Y13, is used for compensating the slightly different electrical lengths of the pulse lines associated with the two channels, thus eliminating the frequency dependence of the phase relations during conversion.

As is shown in Fig. 4-1, the input signal is applied to the two sampling circuits directly without preselection. Thus a minimum frequency dependence of the RF section is achieved over the entire frequency range. The bandwidth of the two channels, which is about 50% of the sampling frequency, is max. 150 kHz. Considering the test bandwidth of the basic unit, this large bandwidth has to be taken into account particularly for measurements on open systems. As mentioned above, each input frequency yields an intermediate frequency which is found from equation (1). Hence any frequency  $f_x$  which meets the following conditions can be evaluated:

$$f_x = (n \pm m) f_o \pm f_2 \pm y \quad n - m \geq 0; \quad y \leq B/2 \quad (2)$$

$$n f_o = f_1 + f_2 \quad (3)$$

$f_1$  = frequency of input signal in channel A

$f_o$  = sampling frequency

$f_x$  = unwanted frequency

$f_2$  = IF (20 kHz)

B = test bandwidth

$n, m = 0, 1, 2 \dots$

When measuring in closed systems where only the test frequency to which the instrument is synchronized exists, the measuring results cannot be falsified.

#### 4.2 Sampling Unit and Amplifier (Y11, Y13)

See circuit diagrams 301.7018 S and 237.1277 S.

In conjunction with the amplifier (Y11, Y13), the thin-film sampling unit constitutes a complete sampling circuit. The input signal is taken to the diode gate via C1. During the interval between the sampling pulses, the diode gate (GL1, 2, 3, 4) is inhibited by the bias voltages produced in the amplifier (BU25.13, 17 in circuit diagram 301.7018 S). The sampling pulses, which are superimposed on the bias, open the gate for a fraction of a nanosecond. During this interval, the capacitor combination  $C_S, C_{GS}, C_4$  is charged in accordance with the voltage applied.

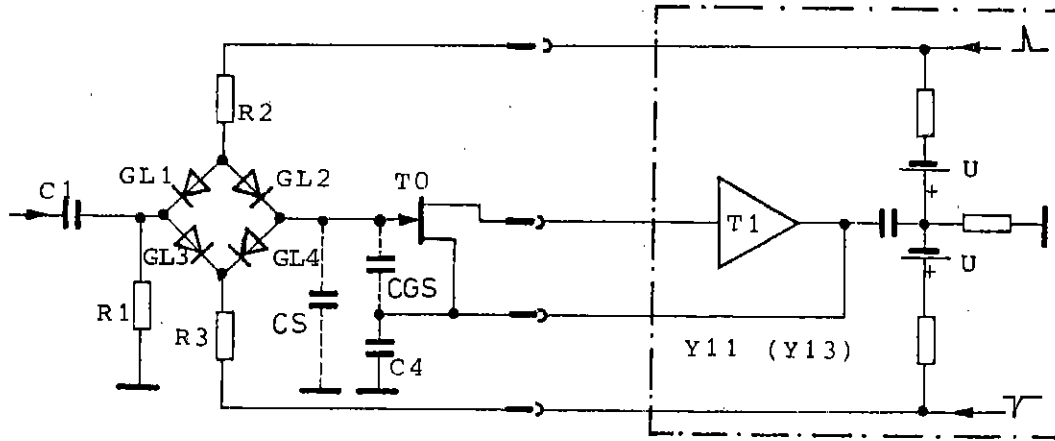


Fig. 4-4 Sampling circuit

During the gate-open time, the capacitors are charged to only a part of the voltage applied. The storage capacitor  $C_s$  (Fig. 4-3), which is realized by the configuration  $C_2$ ,  $C_3$ ,  $C_4$ , is used for restoring the initial amplitude of the signal applied.

The voltage difference occurring across  $C_{GS}$  due to the charge applied is amplified by  $T_0$  and  $T_1$  and returned to the junction point  $C_{GS}$ ,  $C_4$ . The feedback shifts the difference in charge from  $C_{GS}$  to  $C_s$ . Thus the same voltage is present across  $C_{GS}$  as before the sampling procedure, whereas the input voltage with the correct amplitude is available across  $C_4$ .

The driving of the diode bridge in step with the IF signal via  $T_3$  in the amplifier ( $Y_{11}$ ,  $Y_{13}$  in circuit diagram 237.1277 S) suppresses the nonlinear distortion of the IF signal at higher amplitudes. Resistor  $R_1$  (Fig. 4-4) takes the gate of  $T_0$  to a defined DC potential during the sampling procedure.

The bias voltages for the diode gate  $GL_1$  to 4 are produced in the amplifier. The sum of the two voltages is set with  $R_{18}$  and the symmetry is adjusted with  $R_{17}$  for optimum suppression of the residual pulses at the input ( $C_1$ ). The use of a current source  $T_4$  for producing the bias further facilitates the adjustment. To ensure proper functioning of the sampling circuit, two symmetrical pulses which arrive at the same time are required. Symmetrization of the negative pulses coming from pulse generator  $Y_{12}$  takes place in the amplifier, where also the bias voltages are superimposed via  $R_{21}$  and  $R_{22}$ .

The whole sampling unit is produced on a substrate in thin-film technique permitting excellent reproducibility.

#### 4.3 Automatic Frequency Control

See Fig. 4-1 and circuit diagrams 301.7018 S, 237.1231 S, 237.1348 S.

The IF signal of channel A is used as the feedback quantity for the automatic frequency control. The AFC controls the frequency of the voltage-controlled oscillator Y16 and thus also the frequency  $f_o$  of the sampling pulses as a function of the IF offset. The IF is obtained from equation (1) (see section 4.1).

The IF signal from the amplifier of channel A, A11, is applied to input ST28.5 of the synchronization subassembly Y14 (circuit diagram 237.1348 S). The signal is amplified and limited in T1 and B1, whereby disturbing amplitude variations are suppressed. The limited signal carrying the frequency information is applied to the coincidence demodulator of B1. This demodulator functions as a switch: the test signal is chopped at the rate of the reference signal. The mean value of the demodulator output voltage (B1.14) is directly proportional to the phase difference between the two signals. The symmetrical configuration of the demodulator largely suppresses the reference signal, which would otherwise produce crosstalk.

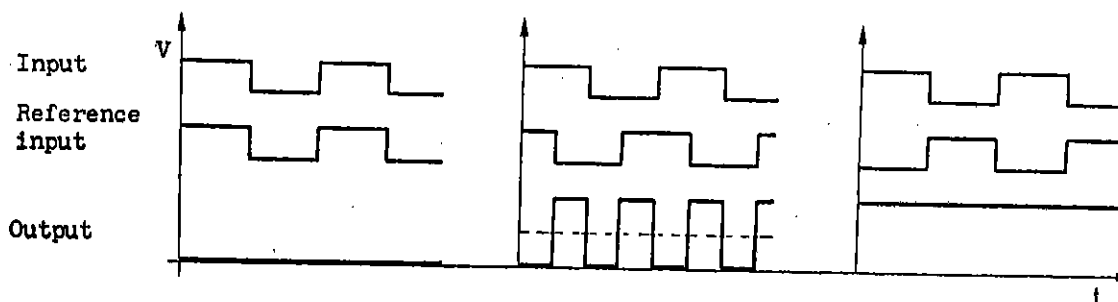


Fig. 4-5 Phase relations at coincidence demodulator B1

The reference signal for the demodulator is produced in the parallel resonant circuit L1-C22, which receives the limited signal coming from B1.8 via the buffer stage T4. The deviation of the intermediate frequency from the resonant frequency is converted into the corresponding phase shift:

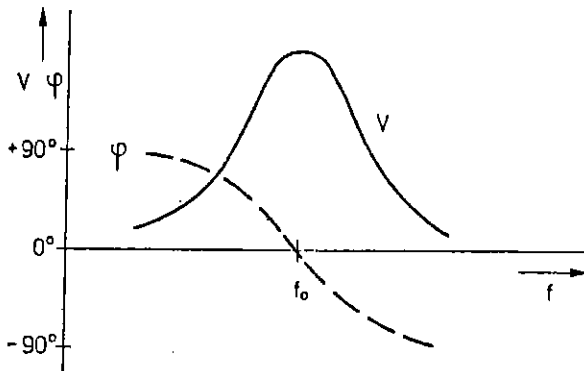
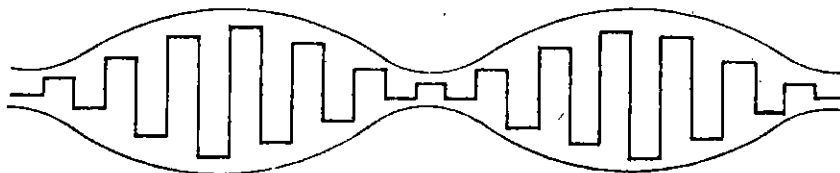


Fig. 4-6 Voltage and phase in the resonant circuit L1-C22

The frequency-dependent amplitude variation of the reference signal is largely suppressed in the diode limiter GL11, GL12, GL13, which is connected after the buffer stage T5. The reference signal is applied to the coincidence demodulator and at the same time used, via C27, as the reference signal for the digital filter in the basic unit. The voltage proportional to the IF deviation is taken, via ST28.15, to the control amplifier Y15 for further processing. The frequency dependence of the amplitude in the resonant circuit is used for obtaining the SYNC bit which is available at ST28.19. The selective amplifier T2 + T3 together with the voltage doubler GL6, 7, 8, 9 produces a voltage used for slowing down the searching oscillator.

During the searching procedure the IF signal applied from the postamplifier to the AFC circuit varies from 0 to  $f_0/2$ . At the highest IF, the signal is amplitude-modulated by other mixture products, which might disturb the correct functioning of the AFC:





For this reason, only the RF component is filtered at input ST28.7 of the synchronization circuit and the ratio of the two IF components is formed in network T7 - R32. If the RF component exceeds the adjusted value, searching is triggered by T9 and thus a wrong lock-in of the control loop is avoided.

In the range 0,3 to 1 MHz, the ratio of the scanning frequency to the intermediate frequency decreases as a function of the input frequency. This leads to an additional phase shift due to the dead time of the sampling mixer (Fig. 4-2). At the same time, the amplitude of the residual pulses at the synchronization input increases. Transistors T10 and T11 correct the modified dynamic conditions. The switching signal is delivered by subassembly Y16 (VCO).

If no signal is available at channel A and thus no IF signal is produced, the searching oscillator T1, T2, T7 included in the AFC amplifier (circuit diagram 237.1231 S) sweeps the voltage-controlled oscillator until the AFC loops starts to operate.

When an IF of about 40 kHz is reached, the DC voltage delivered by amplifier T2, T3 in the synchronization subassembly exceeds the switching threshold of transistor T3 in the control amplifier. Thus the discharging current of C11 is reduced considerably. Consequently the sweep speed of the voltage produced in the searching oscillator decreases. During this transition time, the resonant circuit L1 - C22 (Y14 in circuit diagram 237.1348 S) determining the IF tunes in and the output voltage of operational amplifier B1 reaches its positive maximum value. Thus the discharging current of C11 in the searching oscillator is taken over by B1 and T3 is inhibited. Since only a low current flows, the sweep speed is reduced (Fig. 4-7).

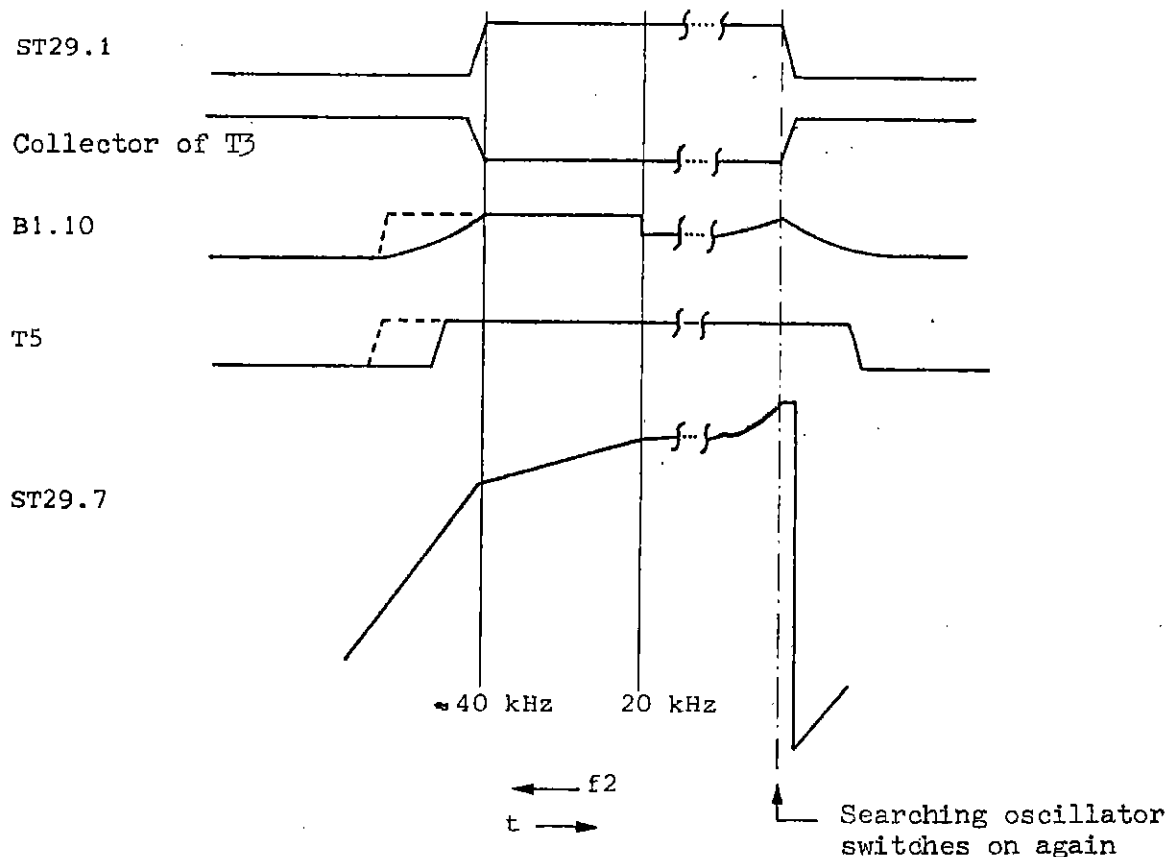


Fig. 4-7 Capture of AFC amplifier Y15

Overlapping of the transition at about 40 kHz is required to avoid disabling of the searching procedure. When the desired IF of 20 kHz is reached, the AFC loop starts to operate, keeping the voltage across C11 at such a value that the difference between  $n$  times the scanning frequency and the input frequency yields an IF of 20 kHz. Thus C11 associated so far with the searching time constant now determines the control time constant in conjunction with R18. The voltage across C11 is delivered via impedance transformer T6 and applied as the control voltage to the variable oscillator Y16. If the voltage across C20 falls below the threshold of Schmitt trigger T4, T5, the searching oscillator is switched on again via T3 and the searching procedure recommences. If the AFC loop has to track a signal of decreasing frequency, the voltage across C11 increases up to +0.6 V. When this value is reached, T1 starts to conduct. The voltage variation at the collector of T1 is inverted in T2 and applied, via T7 and C11 - R18, to the base of T1 as a positive feedback signal. During the discharge of the time-constant network R21 - C12, which determines the return sweep of the searching voltage,

C11 is charged to +5 V. The highest voltage across C11 is fixed by the voltage divider R20, GL7, R25. When the trigger threshold of T2 is exceeded, the return sweep is stopped. T2 and T7 start to conduct and T1 is inhibited. Thus the hold range of the AFC loop is limited to about 6 V. Its searching range is equal to the sweep width of the searching sawtooth of 5 V. The wider hold range is of special advantage for sweeping.

#### 4.4 Variable Oscillator Y16

See circuit diagram 292.0510 S.

The variable oscillator produces the trigger pulses for the pulse generator. The VCO has to meet relatively stringent requirements with respect to the short-term frequency stability. As is explained in 4.1, the instrument uses harmonic mixing up to more than 2000 MHz. Considering the given IF and the resulting bandwidth of the AFC loop, the short-term stability of the VCO frequency should be at least  $5 \times 10^{-6}$ .

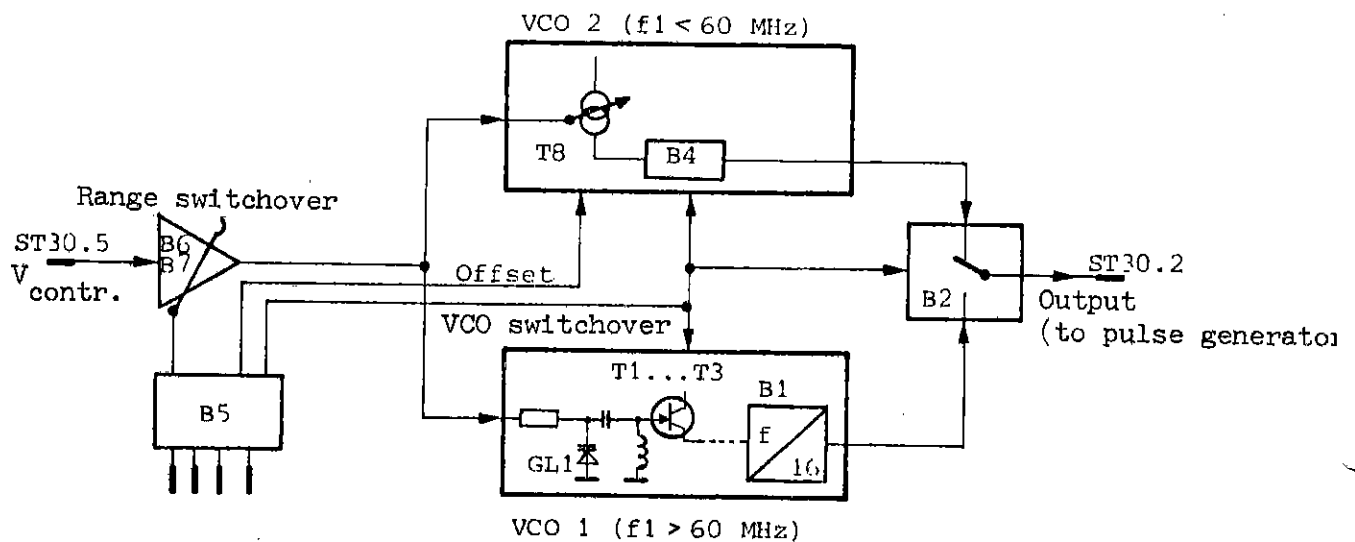


Fig. 4-8 Block diagram of VCO Y16

The variable oscillator Y16 contains the VCO1 used at input frequencies of  $f_1 > 60$  MHz and the VCO2 operative at  $f_1 < 60$  MHz (see Fig. 4-8).

The control voltage arriving at ST30.5 is taken via B6, B7 to the two VCOs and determines their frequency. Depending on the frequency range, the gain of B7 is switched over via the fixed-value memory B5, which also causes

switchover of the two VCOs (B2, T4). The frequency of VCO1 can be adjusted via varactor GL1. The frequency of the VCO1, divided by 16 (B1), is applied to switch B2. The frequency of VCO2 is determined by the controllable current source T8. For frequencies below 1 MHz, T6 conducts and, in addition to C23, C24 determines the frequency range.

The voltage supply of VCO2 is additionally stabilized with B3, thus reducing the spurious deviation and improving considerably the reproducibility of the VCO control characteristic.

#### 4.5 Pulse Generator Y12

See circuit diagrams 237.1290 S and 301.7018 S.

The pulse generator supplies the two sampling units with the sampling pulses. Due to the centralized pulse generation the influence of the sampling-pulse phase variations on the differential phase response of the two sampling stages is suppressed to a large extent.

The TTL-level pulses coming from the VCO are differentiated by C1 - R1 and applied to T1. T1 steepens the edges of these pulses and ensures that T2 is driven to a constant output over the entire frequency range. The two transistors T1 and T2 function as avalanche transistors. In this mode the transistors are operated in the region of the first breakdown voltage. With a sufficient driving level applied to the transistor, the critical point of the collector voltage variation is reached, causing a multiplication of the base current and thus the avalanche-like breakdown of the transistor. After the recovery time  $t_r$ , the collector voltage  $V_C$  increases exponentially until it reaches the supply voltage  $V_B$ .

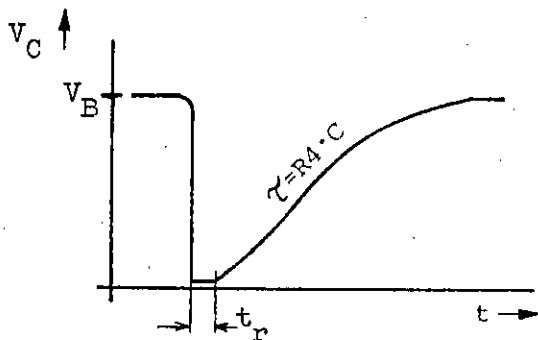


Fig. 4-9 Voltage characteristic at the collector of T2

The abrupt rolloff of the collector voltage is differentiated by C3 (C4) and, after symmetrization, applied to the sampling stages via diode switches GL52 and GL53 (circuit diagram 301.7018 S). These diode switches ensure sufficient decoupling of the two channels. Due to the current injected by the pulse generator via R8 (R7) the shunt diode GL1 (Fig. 4-10) conducts. The voltage drop across GL1 inhibits diode GL2; it is made conductive only by the negative pulses coming from the pulse generator.

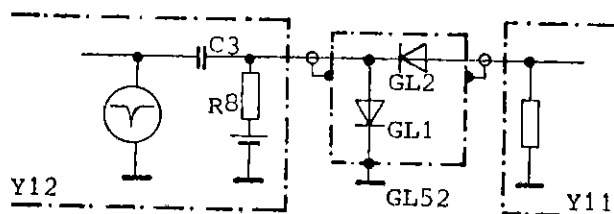


Fig. 4-10 Application of the scanning pulses via diode switches  
(component Nos apply to channel A)

#### 4.6 Control Board Y22

See circuit diagram 301.7360 S.

The control board permits a certain frequency subrange to be switched in. The four-bit counter B4 gives the selected range in binary coding. The count can be manually increased and decreased via the control lines ST35.a9, b9, using the two front-panel buttons 3 and 4. In addition, the counter can be set at will by the microprocessor of the basic unit via the data lines ST33.a6, a5, a4, a3 and the strobe line St33.b4. B5 and B6 decode the count and drive the LEDs for indicating the frequency subrange on the LED board Y21.

Since only 14 of the binary combinations 0 to 15 are associated with the frequency subranges, the microprocessor of the basic unit causes switching through the 14 subranges in both directions.

Both the count and the plug-in identification with the synchronization bit can be taken to the data bus via B10 and the bus driver B11 and read in by the processor.

B1I and B1II are used for locking the two pushbuttons 3 and 4 in the case of remote control and for extinguishing the frequency range indicators when the autoranging facility is used.

## 5. Repair

### 5.1 Required Measuring Instruments and Accessories

The measuring instruments listed under 3.1 are required. In addition, the following equipment is necessary:

- Squarewave generator, 100 to 200 kHz,  $V_{out}$  20 mV<sub>pp</sub>
- Oscilloscope, 0 to 30 MHz, vert. 1 mV/cm, horiz. 0.5  $\mu$ s to 20 ms

### 5.2 Assembly

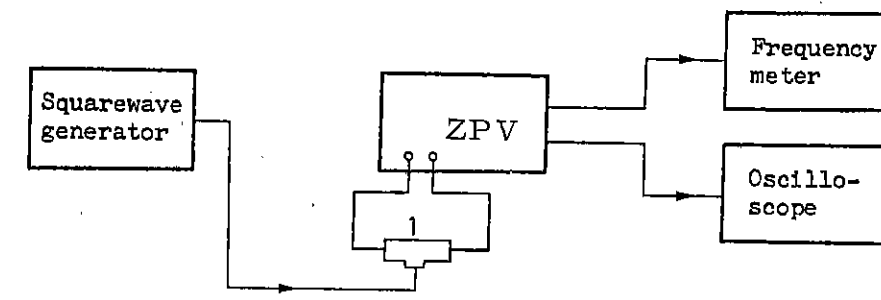
For checking the adjustment of guiding pin and connector strip on the rear panel, remove the upper cover of the basic unit ZPV. The guiding pin and the connector strip should be adjusted such that perfect insertion and reliable contact making are ensured. Tighten the nuts of the phase shifter Y19 such that the rotor disk can be turned. Then insert the plug-in into the basic unit and fit the different subassemblies.

### 5.3 Adjustments

The position of the subassemblies and adjustment controls is shown in Fig. 5-1 (in the Appendix).

#### 5.3.1 Sampling Stages

##### Test setup

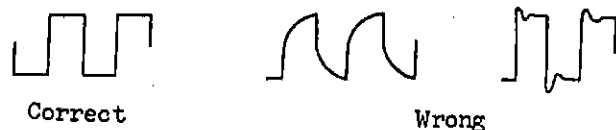


1 Feed Unit ZPV - Z2

### Preliminary adjustment of amplifier Y11, Y13

Select the manual frequency range selection on the basic unit ZPV. The indicator FREQ. STOP AUTORANGING should light up. As well, one of the green LEDs associated with the frequency subrange indication 2 (Fig. 2-1) should light up. Buttons 3 and 4 should permit successive selection of the frequency subranges in the correct order. For further adjustments, select the range 600 - 1000 MHz. Use the oscilloscope to check the correct functioning of the VCO Y16 and of the pulse generator Y12. To this effect, apply the probe of the oscilloscope close to transistor T2 in the pulse generator and set R12 to mid-position. Steep negative-going pulses of about 3 MHz appear on the screen. If the pulses are missing, check the VCO output (ST30.2) and input (ST30.5). The signal at pin 5 should be a sawtooth of about 5 V and that at pin 2 a square wave of  $\geq 3 V_{pp}$  on which a +5-V bias is superimposed. For measuring connect the board via one of the two adapter boards which are included in the ZPV. However, these boards cannot be used for pulse measurements on Y11, Y12 and Y13. Also use the oscilloscope to check whether a DC voltage of +0.6 V is present at the output (K27) of phase shifter Y19. If required, turn the rotor of the phase shifter accordingly.

Select a frequency of about 200 kHz with the duty cycle 2 (period/mark ratio) on the squarewave generator. The voltages across the channels A and B should be  $100 mV_{pp}$ . Connect the oscilloscope to the cursor of R3 in the amplifier Y11 and turn R3 to the lefthand stop. Use R18 to set the bias and R17 to coarsely adjust the symmetry such that the waveform at R3 corresponds to that at the input sockets. In the case of a wrong adjustment, the IF signal is distorted:



Connect channel A of the ZPV - E3 directly to the oscilloscope and use R17 in the amplifier Y11 to adjust the minimum of the residual pulses; their amplitude should not exceed  $10 \text{ mV}_{pp}$ . Reconnect the channel and use R3 to adjust for the same amplitude of the IF voltage as at the input socket.

Amplifier Y13 associated with channel B is adjusted in the same way.

### 5.3.2 Synchronization Circuit Y14 and AFC Amplifier Y15

The same test setup as under 5.3.1 is used. The squarewave generator is replaced by a sinewave generator ( $f = 5 \text{ kHz to } 2 \text{ MHz}$ ).

Set the frequency of the generator to 20 kHz and its output voltage to about 300 mV. Connect the oscilloscope to the base of T5 in the synchronization circuit Y14 and use L1 to adjust the voltage maximum.

For voltage measurement, connect an oscilloscope to the collector of T3 in the AFC amplifier Y15. Use R8 (Y15) to adjust for a voltage of -2 V. This stops the searching oscillator.

When reducing the input frequency below 5 kHz, the searching oscillator should remain in circuit. When increasing the signal generator frequency above 20 kHz, the searching frequency of about 100 Hz (adjustable with R22) is switched over to a few hertz. Increasing the generator frequency still further brings the searching frequency again to the value adjusted with R22 (the capture mode of the AFC loop is explained under 4.3). However, the switchover of the searching frequency should not occur below 24 kHz. In the range from the slowing down of the searching procedure to 20 kHz, the searching oscillator should not be disconnected.

Connect the oscilloscope to ST29.7 and vary the signal generator frequency over the range from about 100 kHz to 5 kHz. The searching frequency should be reduced in any case at 24 kHz and at 20 kHz the searching procedure should be stopped. In the case of slow searching the output voltage at B1.10 (Y15) should be at least +8 V. At a generator frequency of  $< 20 \text{ kHz}$  searching should be enabled again.

Set the frequency of the generator to 1.4 MHz and its output voltage to about 200 mV. The red lamp UNSYNC on the front panel should light up. Select the frequency range 1 to 2 MHz using the corresponding pushbuttons.

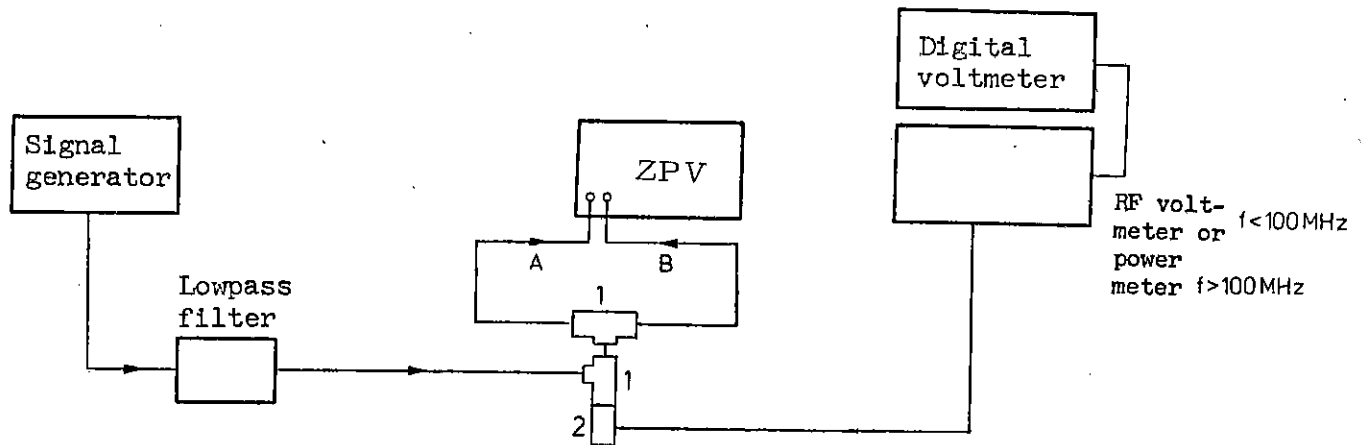


Now the red indicator should go out. Connect the frequency meter to the IF output of channel B ( $Z_{out} = 1 \text{ k}\Omega$ ).

Use L1 in the synchronization circuit Y14 to adjust for 20 kHz  $\pm$ 10 Hz in accordance with the frequency meter. Connect the oscilloscope to the output of operational amplifier B1 (= C6, C9) in the AFC amplifier Y15. Use L1 and L2 to adjust for maximum suppression of the 40-kHz and 20-kHz signals at this checkpoint.

### 5.3.3 Amplifiers Y11, Y13

#### Test setup



- 1 Feed Unit ZPV - Z2
- 2 RF voltmeter probe ( $f < 100 \text{ MHz}$ )  
or power meter probe ( $f > 100 \text{ MHz}$ )

Set the signal generator frequency to 2 MHz. Adjust the level to 200 mV in accordance with the RF voltmeter. Select the range 2 to 3 MHz on the Tuner ZPV - E3 and mode B, LIN on the basic unit ZPV. Disconnect the channel B from the feed unit. Lamp UNSYNC should not light up. The ZPV indicates only the inherent noise. The indicated noise should not considerably exceed 30  $\mu$ V. If necessary, use R12 in the pulse generator Y12 to adjust for minimum noise. Restore the test setup shown in the above figure. Select the modes A (B), LIN. The indicated values should be 100 mV. If required, adjust R3 in the amplifier Y11 or Y13.

The RF voltmeter with the 10-dB attenuator is replaced by the Microwave Power Meter NRS. When using different power meters, the attenuator should remain in circuit and be considered for the measurement. Set a signal generator frequency of 1900 MHz, connect the lowpass filter accordingly and

adjust the signal generator level such that the power meter indicates 0.8 mW. Select the range 1000 to 2000 MHz on the ZPV - E3. In the mode B, LIN use R18 (Y13) to adjust for 100 mV on the display and check the setting of R17 (see under 5.3.1 "preliminary adjustment of amplifier"). Perform the same adjustments for channel A.

Set the signal generator frequency to 500 MHz and check the calibration. Replace the power meter by the voltmeter and verify the calibration at 300 kHz and an input voltage of 100 mV. The deviations should not exceed the values given in the specifications.

#### 5.3.4 Phase Shifter Y19

The test setup is the same as under 3.2.3.

Select the autoranging mode and the measuring mode A (B), LIN on the basic unit. Set the frequency of the signal generator to 1 MHz and its level to 100 to 200 mV in accordance with the ZPV indication.

Store the reference phase using button  $\phi$  REF. STORE.

Increase the generator frequency to about 1500 MHz and adjust the indicated phase to  $0^\circ$  using phase shifter Y19. After the adjustment, the nuts of the phase shifter should be well tightened. Next check the phase response, referred to 1 MHz, over the entire frequency range. The deviations should not exceed the values given in the specifications.

#### 5.3.5 Differential Amplitude/Frequency Response

The test setup is the same as under 3.2.3.

Set the frequency of the signal generator to 1 MHz and the level to 100 mV in accordance with the ZPV indication. Select mode B/A, LIN. Store the reference value using button LEVEL REF. STORE. Check the ratio of the two voltages over the entire frequency range. The test results should meet the requirements of the specification.

#### 5.3.6 Channel Crosstalk

See section 3.2.5.

### 5.3.7 VCO Ranges

The test setup is the same as under 5.3.1. Use a signal generator instead of the squarewave generator.

#### VCO 2

Select the frequency range 0.3 to 1 MHz on the ZPV - E2. Reduce the signal generator frequency from 1 MHz to 250 kHz. The set should be synchronized to at least 300 kHz. Increase the frequency starting at about 250 kHz until synchronization is effective again. The frequency at which lamp UNSYNC goes out should not exceed 300 kHz. If necessary, use C24 for correction.

#### VCO 1

Select the frequency range 60 to 100 MHz on the ZPV - E2. Set the signal generator frequency to 60 MHz and reduce it continuously. When resynchronizing the frequency control (lamp UNSYNC lights up briefly), no reception gap should occur, i.e. lamp UNSYNC should not be on continuously and no permanent searching should be measured at ST30.5. If necessary, use R5 for correction.